## Optical Components for Polarization Analysis of Soft X-ray Radiation

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Periodic multilayer mirrors consisting of alternating layers of Co/C, Ni/Ti or Ni/V have been produced by sputter deposition. The period has been chosen such that the first Bragg peak appears at the Brewster angle ( $\Theta \approx 45^{\circ}$ ) if the energy of the radiation is close to the K edge of C or the L<sub>3</sub> edges of Ti or V, respectively. The reflectances R<sub>s</sub> and R<sub>p</sub> of these mirrors in s- and p-polarization geometry have been measured at beamline PM4 of BESSY I using the BESSY polarimeter [1] and a 10 µm wide exit slit to get good energy resolution ( $E/\Delta E \ge 300$ ). The measured maximum values close to the relevant edges were R<sub>s</sub> = 18.3% and R<sub>s</sub>/R<sub>p</sub> = 13.4 for Co/C, R<sub>s</sub> = 6.0% and R<sub>s</sub>/R<sub>p</sub> = 5.6 for Ni/Ti, R<sub>s</sub> = 8.5 % and R<sub>s</sub>/R<sub>p</sub> = 5.3 for Ni/V. The beam available at PM4 contains a considerable amount of circular polarization, which has been determined at the K edge of carbon and can be estimated for the L edges of Ti and V. For a purely linearly polarized beam with the same value of  $E/\Delta E$  the corrected values are R<sub>s</sub> = 21.6% and R<sub>s</sub>/R<sub>p</sub> = 37 for our Co/C multilayer; R<sub>s</sub> = 6.8% and R<sub>s</sub>/R<sub>p</sub> > 8 for Ni/Ti; R<sub>p</sub> = 9.5% and R<sub>s</sub>/R<sub>p</sub> > 7.5 for Ni/V. These figures show that the three multilayer mirrors are suitable to be used as analysers for polarization analysis close to the respective absorption edges.

[1] F. Schäfers et al., Applied Optics, 38 (1999) 4074-4088.